

Notice of References Cited	Application/Control No. 10/511,482	Applicant(s)/Patent Under Reexamination IWAMURA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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	N	JP 2003-100273	04-2003	Japan	Masuda et al	H01M 2/10
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NON-PATENT DOCUMENTS

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